

**Characterisation of 1200 V RB-IGBTs with different irradiation levels under hard and soft switching conditions**

**Blinov, Andrei; Korkh, Oleksandr; Vinnikov, Dmitri;** Waind, Peter 2018 20th European Conference on Power Electronics and Applications (EPE'18 ECCE Europe) : Riga, Latvia, 17-21 September 2018 2018 / p. 1382-1391 : ill <https://ieeexplore.ieee.org/document/8515535>

**Operation of Single-Chip MOSFET and IGBT Devices after failure due to repetitive avalanche [Electronic resource]**

**Blinov, Andrei;** Norrga, Staffan; Tibola, Gabriel EPE'15 ECCE Europe : 8-10 September 2015, Geneva, Switzerland : 17th European Conference on Power Electronics and Applications 2015 / p. 1-9 : ill. [USB] <http://dx.doi.org/10.1109/EPE.2015.7309190>

**Reliability analysis of micro-inverters considering PV module variations and degradation rates**

**Liivik, Elizaveta;** Sangwongwanich, Ariya; Blaabjerg, Frede 2018 20th European Conference on Power Electronics and Applications (EPE'18 ECCE Europe) : Riga, Latvia, 17-21 September 2018 2018 / p. 1475-1482 : ill <https://ieeexplore.ieee.org/document/8515325>